

J ournal of I ntegrated C ircuits and S ystems

Volume 4 • Number 2 • **September 2009** • ISSN 1807-1953

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The **Journal of Integrated Circuits and Systems (JICS)** is a publication from SBMicro – Brazilian Microelectronics Society and SBC – Brazilian Computer Society whose are non-profit scientific societies aiming to foster the microelectronics and computer science teaching, research and development.

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FOREWORD

This issue of Journal of Integrated Circuits and Systems (JICS) includes papers on process, materials, devices, and modeling. These papers have been selected from the presentations given at SBMicro2008 (23rd Symposium on Microelectronics Technology and Devices), which has been held in Gramado, Brazil in 2008. Among the contributions presented at SBMicro2008 conference, only a few best rated by the reviewers were selected by the JICS Editorial Board and have been invited to submit an extended version. These papers have been submitted to usual reviewing process with the help of external experts. An invited paper from Dr. Carlos Mazure on SOI technology and its applications is included in this issue and also spontaneous submissions have been considered.

We would like to thank the authors for their effort in preparing these high quality papers, as well as the reviewers for their help on paper selection, which guarantees the scientific level of this issue. We sincerely hope that JICS readers will enjoy these contributions.

João Antonio Martino
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JICS Co-Editor

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